



## Gallium Nitride 28V 15W, RF Power Transistor

### Description

The GTAH35015M2 is a 15W GaN HEMT, designed for multiple applications, especially sub-6GHz MC-GSM/WCDMA/LTE/LTE-A from up to 6000MHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.



- Typical performance (on 4.4-5GHz and 3.4-3.8GHz fixture with device soldered)

$V_{DD}=28V$   $I_{DQ}=120mA$ , Pulse CW, Pulse width=12uS, Duty cycle=10%.

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
4400	42.68	18.5	58.5	10.55	43.85	24.3	64.1
4500	42.79	19.0	59.6	10.83	43.91	24.6	65.2
4600	42.7	18.6	59.5	10.94	43.84	24.2	64.6
4700	42.75	18.9	64.0	11.26	43.97	24.9	69.0
4800	42.25	16.8	65.6	11.25	43.56	22.7	70.3
4900	41.15	13.0	64.0	11.4	42.78	19.0	69.1
5000	40.04	10.1	57.7	10.93	41.93	15.6	65.3

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
3400	41.56	14.3	58.9	13.19	42.68	18.5	63.0
3500	41.52	14.2	62.5	13.57	42.61	18.3	65.2
3600	41.36	13.7	62.8	13.76	42.44	17.5	64.8
3700	41.07	12.8	63.4	13.84	42.26	16.8	64.9
3800	40.59	11.5	62.9	13.58	41.92	15.6	65.2

Other available application: 0.8-3.5GHz

### Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

### Important Note: Proper Biasing Sequence for GaN HEMT Transistors

#### Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (28V)
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

#### Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS



**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain--Source Voltage	$V_{DSS}$	150	Vdc
Gate--Source Voltage	$V_{GS}$	-10,+2	Vdc
Operating Voltage	$V_{DD}$	32	Vdc
Maximum Forward Gate Current @ $T_c = 25^\circ\text{C}$	$I_{gmax}$	4	mA
Storage Temperature Range	$T_{stg}$	-65 to +150	$^\circ\text{C}$
Case Operating Temperature	$T_c$	+150	$^\circ\text{C}$
Operating Junction Temperature(See note 1)	$T_j$	+225	$^\circ\text{C}$
Total Device Power Dissipation (Derated above $25^\circ\text{C}$ , see note 2)	$P_{diss}$	32	W

Note: 1. Continuous operation at maximum junction temperature will affect MTTF  
2. Bias Conditions should also satisfy the following expression:  $P_{diss} < (T_j - T_c) / R_{JC}$  and  $T_c = T_{case}$

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case $T_c = 85^\circ\text{C}$ , $T_j = 200^\circ\text{C}$ , RF CW operation, <b>FEA mode</b>	$R_{\theta JC}$	5.7	C/W

**Table 3. Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise noted)

**DC Characteristics**

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS} = -8\text{V}$ ; $I_{DS} = 4\text{mA}$	$V_{DSS}$	150			V
Gate Threshold Voltage	$V_{DS} = 28\text{V}$ , $I_D = 4\text{mA}$	$V_{GS(th)}$		-2.7		V
Gate Quiescent Voltage	$V_{DS} = 28\text{V}$ , $I_{DS} = 100\text{mA}$ , Measured in Functional Test	$V_{GS(Q)}$		-2.27		V

**Functional Tests (In 3.4-3.8GHz Production fixture, 50 ohm system) :**  $V_{DD} = 28\text{Vdc}$ ,  $I_{DQ} = 100\text{mA}$ ,  $f = 3.6\text{GHz}$ , WCDMA, Pulse CW

Characteristic	Symbol	Min	Typ	Max	Unit
Power Gain @ $P_{sat}$	$G_p$		17		dB
Drain Efficiency @ $P_{sat}$	$Eff$		65		%
Saturated Power by CCDF test	$P_{SAT}$	16			W
Input Return Loss	IRL		-7		dB
Mismatch stress at all phases (Device no damage)	VSWR		10:1		$\Psi$



**TYPICAL CHARACTERISTICS**  
**3.4-3.8GHz**

Figure 1. Power gain and drain efficiency as function of average load power

Vdd=28V, Idq=100mA, Pulsed condition: 12us, 10%

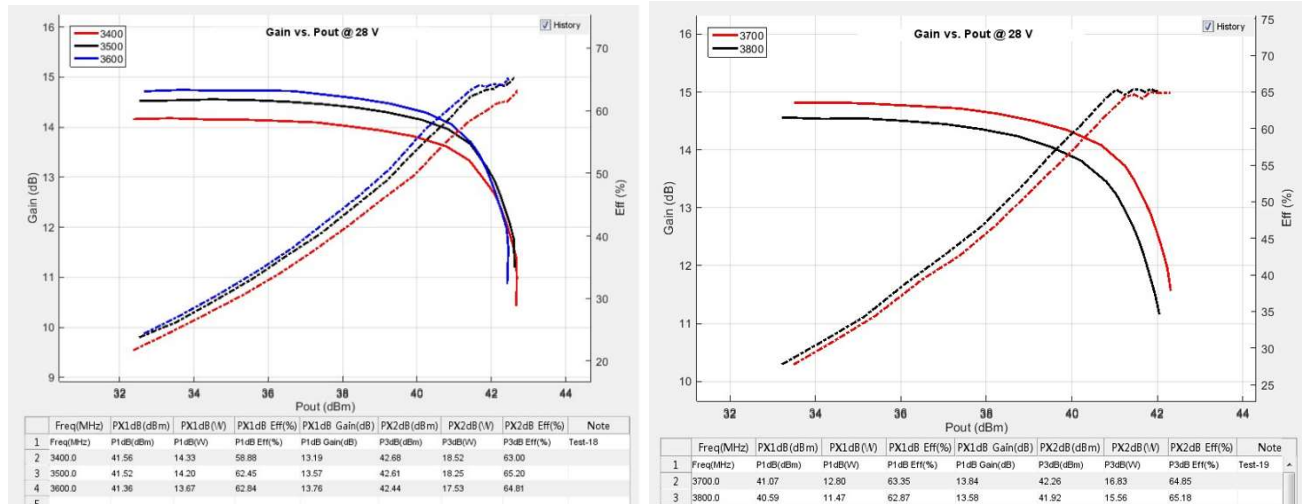


Figure 2. Network analyzer plots (S11/S21)

Vdd=28V, Idq=100mA



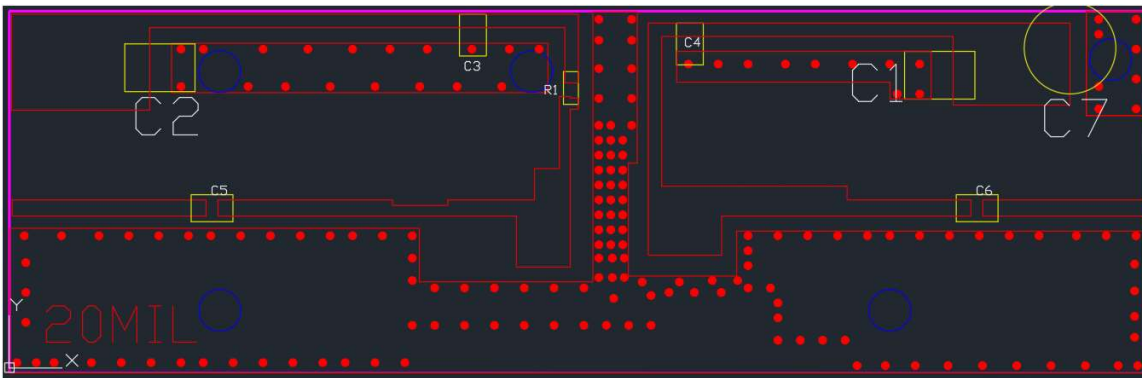


Table 3. 1 Carrier WCDMA RF performance (Input CCDF: 10dB)

Freq (MHz)	Pout (dBm)	CCDF (dB)	Ppeak (dBm)	Ppeak (W)	ACPR (dBc)	Gain (dB)	Efficiency (%)
3400	32.02	9.40	41.42	13.9	-45.7	14.1	21.9
3500	32.01	9.43	41.43	13.9	-45.2	14.5	22.8
3600	32.00	9.39	41.39	13.8	-45.0	14.7	23.3
3700	32.03	9.37	41.39	13.8	-44.4	14.8	24.0
3800	32.01	9.14	41.15	13.0	-43.1	14.5	24.7

Figure 4. test fixture ,BOM and layout (Layout file upon request,)

PCB: 20 Mil Rogers 4350B

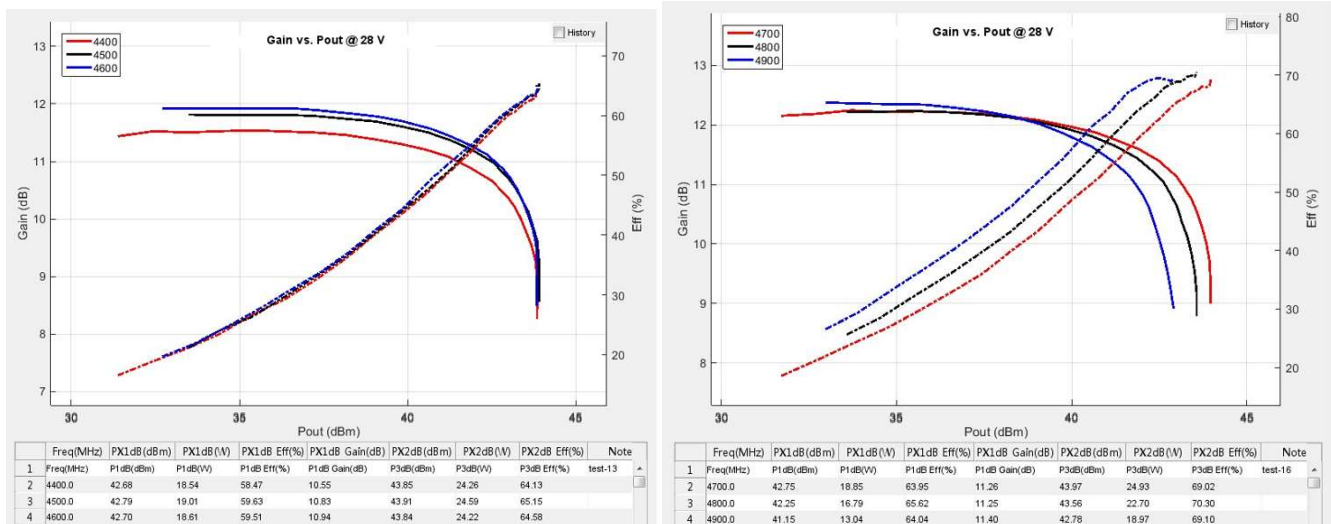


Designator	Value	Quantity	Package
C1 C2	10 uF	2	1210
C3 C4 C5 C6	8.2pF	4	0805
C7	470uF	1	
R1	10ohm	1	0805

4.4-5GHz

Figure 1. Power gain and drain efficiency as function of average load power

Vdd=28V, Idq=100mA, Pulsed condition: 12us, 10%



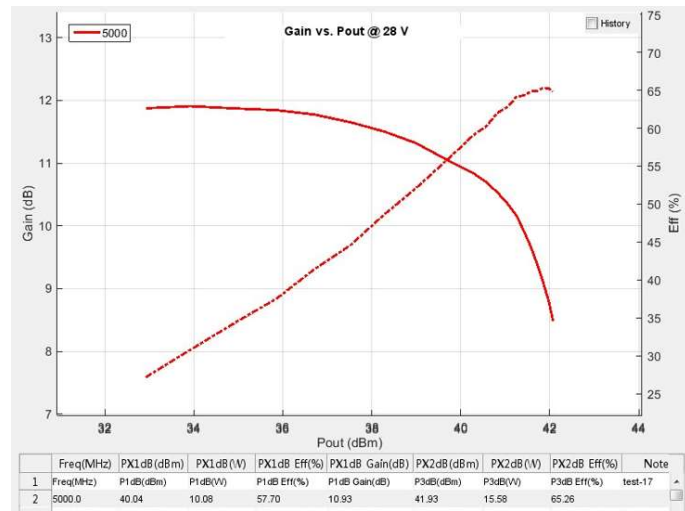


Figure 2. Network analyzer plots (S11/S21)

Vdd=28V, Idq=100mA

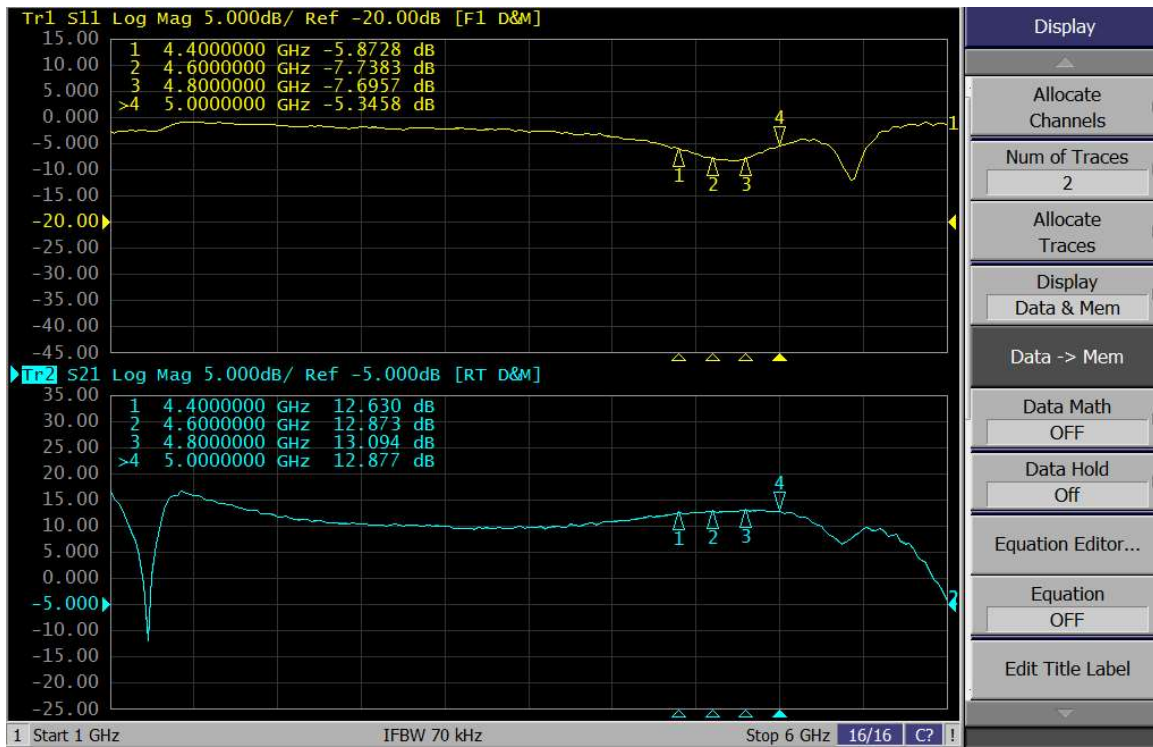


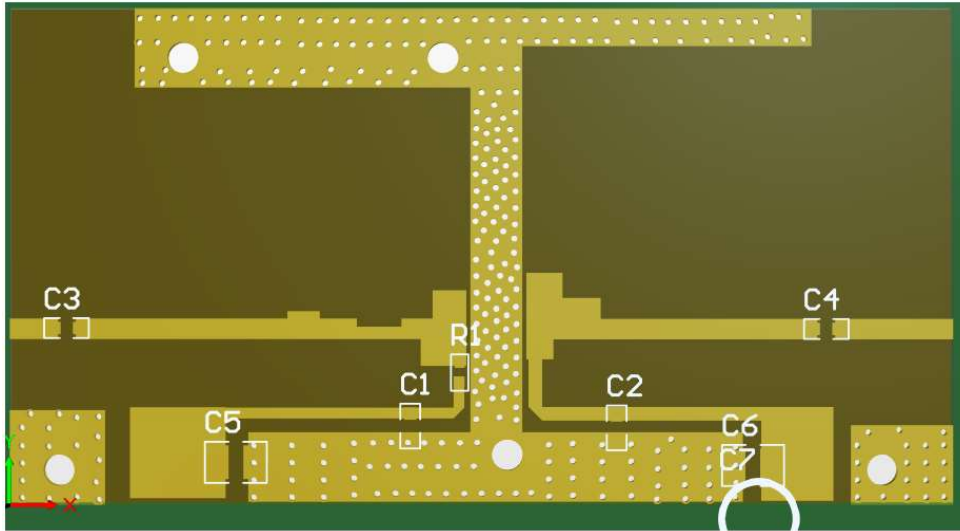
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4400	32.03	9.29	41.33	13.6	-44.0	11.4	19.1
4500	32.01	9.41	41.42	13.9	-44.4	11.7	19.1
4600	32.00	9.22	41.22	13.2	-43.3	11.8	19.2
4700	32.01	9.34	41.34	13.6	-42.8	12.1	20.4
4800	32.01	9.29	41.29	13.5	-43.8	12.2	22.3
4900	32.00	8.96	40.96	12.5	-41.9	12.3	24.2
5000	32.01	8.81	40.82	12.1	-40.5	11.7	25.0



Figure 4. test fixture ,BOM and layout (Layout file upon request,)

PCB: 30 Mil Rogers 4350B

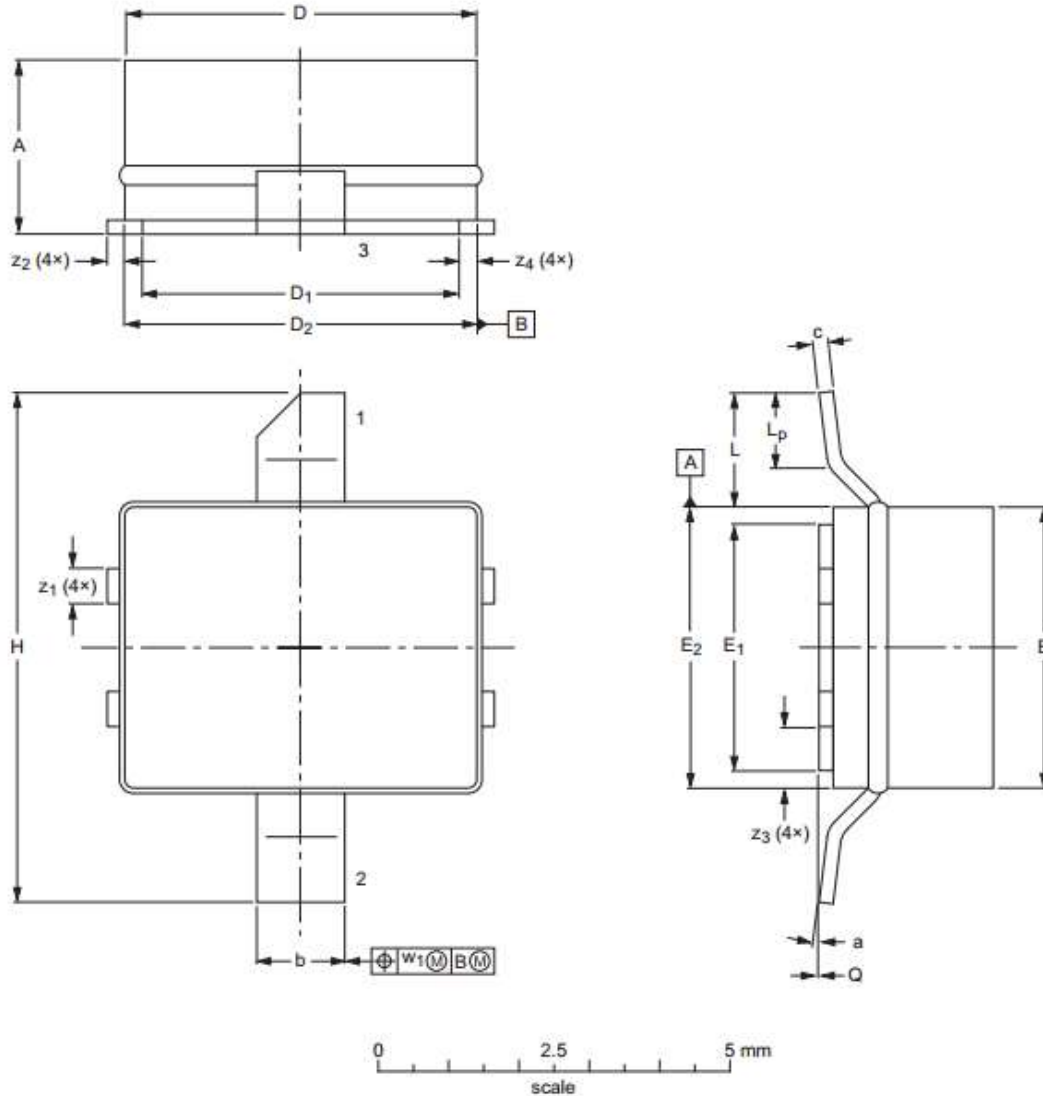


Designator	Value	Quantity	Package
C1 C2 C3 C4	5.6 pF	5	0805
C5 C6	10uF	4	1210
C7	470uF	1	
R1	10ohm	1	0603



## Package Outline

Earless Flanged ceramic package; 2 leads(1-Drain,2-Gate,3-Source)



UNIT	A	b	c	D	D <sub>1</sub>	E	E <sub>1</sub>	E <sub>2</sub>	H	L	L <sub>p</sub>	Q	w <sub>1</sub>	z <sub>1</sub>	z <sub>2</sub>	z <sub>3</sub>	z <sub>4</sub>	α
mm	2.34	1.35	0.23	5.16	4.65	4.14	3.63	4.14	7.49	2.03	1.02	0.1	0.25	0.58	0.25	0.97	0.51	7°
	2.13	1.19	0.18	5.00	4.50	3.99	3.48	3.99	7.24	1.27	0.51	0.0		0.43	0.18	0.81	0.00	0°

OUTLINE VERSION	REFERENCE			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
PKG-MM					18/6/2014





## Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2017/6/26	V1.0	Objective Datasheet Creation
2017/7/27	V1.0	Preliminary datasheet creation
2017/12/5	V1.1	Add mounting instructions
2017/12/27	V1.2	Add 0.8-3.5GHz wideband performance
2018/3/7	V1.3	Upper frequency modified
2021/12/2	V1.4	Using 3.4-3.8GHz, 4.4-5GHz application to specify the device

Application data based on ZXY-21

### Notice

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